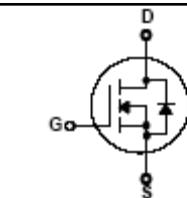


## HFS5N40 400V N-Channel MOSFET

### FEATURES

- Originative New Design
- Superior Avalanche Rugged Technology
- Robust Gate Oxide Technology
- Very Low Intrinsic Capacitances
- Excellent Switching Characteristics
- Unrivalled Gate Charge : 13 nC (Typ.)
- Extended Safe Operating Area
- Lower  $R_{DS(ON)}$  : 1.27 Ω (Typ.) @ $V_{GS}=10V$
- 100% Avalanche Tested

$BV_{DSS} = 400 V$   
 $R_{DS(on)\ typ} = 1.27 \Omega$   
 $I_D = 3.0 A$



### Absolute Maximum Ratings $T_C=25^\circ C$ unless otherwise specified

Symbol	Parameter	Value	Units
$V_{DSS}$	Drain-Source Voltage	400	V
$I_D$	Drain Current – Continuous ( $T_C = 25^\circ C$ )	3.0*	A
	Drain Current – Continuous ( $T_C = 100^\circ C$ )	1.9*	A
$I_{DM}$	Drain Current – Pulsed (Note 1)	12*	A
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	510	mJ
$I_{AR}$	Avalanche Current (Note 1)	3.0	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	7.0	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	4.5	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ C$ )	35	W
	– Derate above $25^\circ C$	0.28	W/ $^\circ C$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ C$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ C$

\* Drain current limited by maximum junction temperature

### Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	3.57	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient	--	62.5	

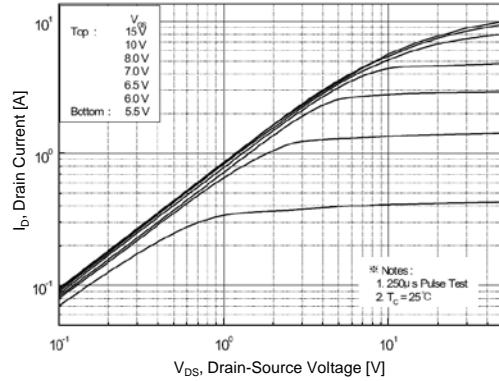
**Electrical Characteristics**  $T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>On Characteristics</b>						
$V_{GS}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2.5	--	4.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 1.5 \text{ A}$	--	1.27	1.6	$\Omega$
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$	400	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.38	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 400 \text{ V}$ , $V_{GS} = 0 \text{ V}$	--	--	1	$\mu\text{A}$
		$V_{DS} = 320 \text{ V}$ , $T_C = 125^\circ\text{C}$	--	--	10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}$ , $V_{DS} = 0 \text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}$ , $V_{DS} = 0 \text{ V}$	--	--	-100	nA
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $f = 1.0 \text{ MHz}$	--	450	590	pF
$C_{oss}$	Output Capacitance		--	70	90	pF
$C_{rss}$	Reverse Transfer Capacitance		--	10	17	pF
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Time	$V_{DS} = 200 \text{ V}$ , $I_D = 4.5 \text{ A}$ , $R_G = 25 \Omega$  (Note 4,5)	--	15	30	ns
$t_r$	Turn-On Rise Time		--	70	140	ns
$t_{d(off)}$	Turn-Off Delay Time		--	30	60	ns
$t_f$	Turn-Off Fall Time		--	40	80	ns
$Q_g$	Total Gate Charge	$V_{DS} = 320 \text{ V}$ , $I_D = 4.5 \text{ A}$ , $V_{GS} = 10 \text{ V}$  (Note 4,5)	--	13	17	nC
$Q_{gs}$	Gate-Source Charge		--	4.0	--	nC
$Q_{gd}$	Gate-Drain Charge		--	6.0	--	nC
<b>Source-Drain Diode Maximum Ratings and Characteristics</b>						
$I_S$	Continuous Source-Drain Diode Forward Current		--	--	3.0	A
$I_{SM}$	Pulsed Source-Drain Diode Forward Current		--	--	12	
$V_{SD}$	Source-Drain Diode Forward Voltage	$I_S = 3.0 \text{ A}$ , $V_{GS} = 0 \text{ V}$	--	--	1.5	V
$trr$	Reverse Recovery Time	$I_S = 4.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$ $dI_F/dt = 100 \text{ A}/\mu\text{s}$ (Note 4)	--	190	--	ns
$Qrr$	Reverse Recovery Charge		--	1.0	--	$\mu\text{C}$

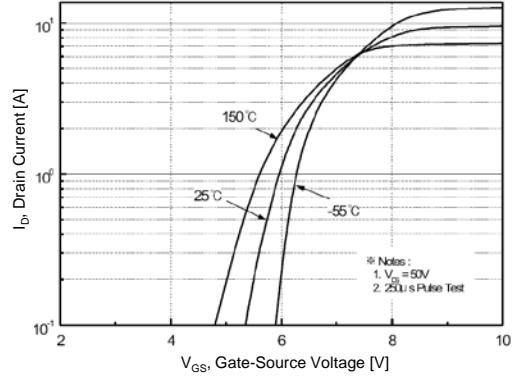
**Notes :**

- Repetitive Rating : Pulse width limited by maximum junction temperature
- $L=44\text{mH}$ ,  $I_{AS}=4.5$ ,  $V_{DD}=50\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$
- $I_{SD}\leq 3.0\text{A}$ ,  $di/dt\leq 200\text{A}/\mu\text{s}$ ,  $V_{DD}\leq BV_{DSS}$ , Starting  $T_J=25^\circ\text{C}$
- Pulse Test : Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
- Essentially Independent of Operating Temperature

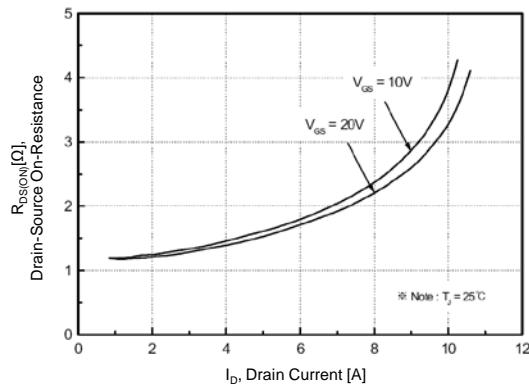
## Typical Characteristics



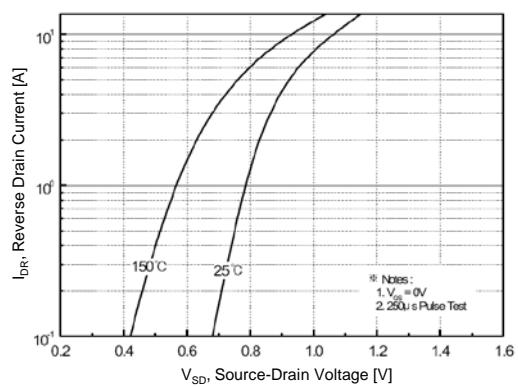
**Figure 1. On Region Characteristics**



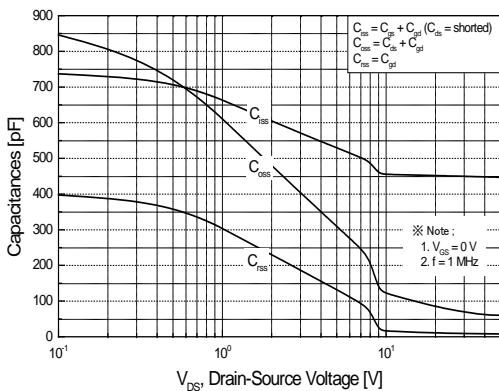
**Figure 2. Transfer Characteristics**



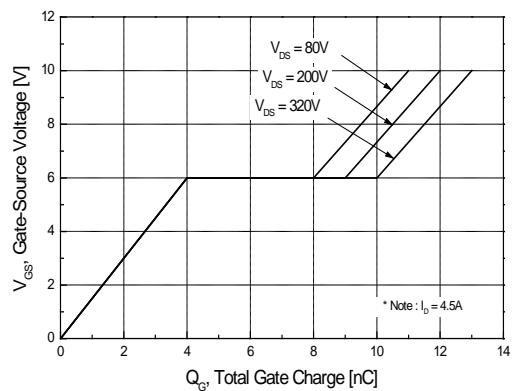
**Figure 3. On Resistance Variation vs. Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**

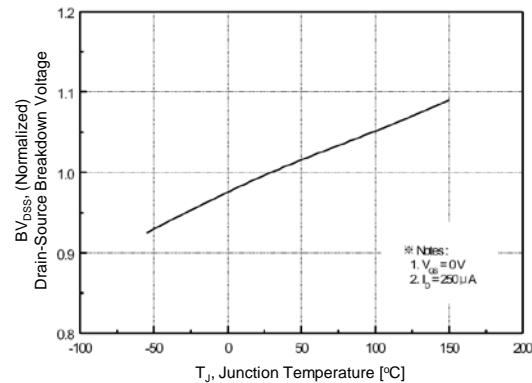


**Figure 5. Capacitance Characteristics**

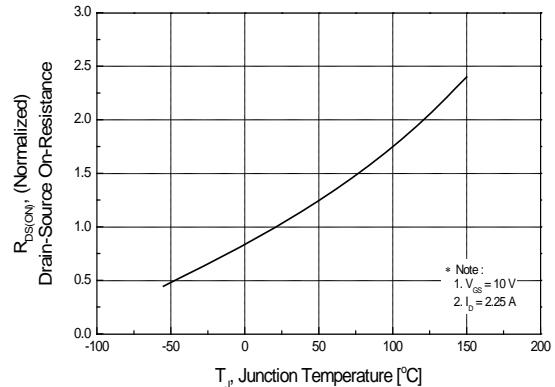


**Figure 6. Gate Charge Characteristics**

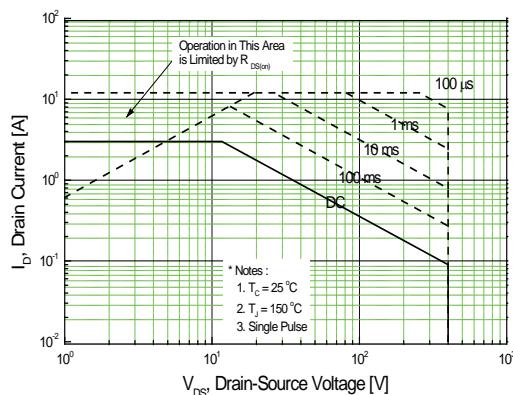
## Typical Characteristics (continued)



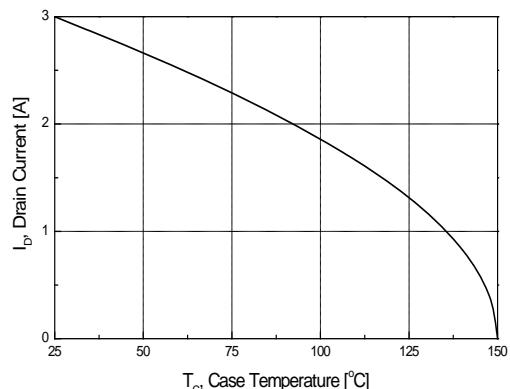
**Figure 7. Breakdown Voltage Variation vs Temperature**



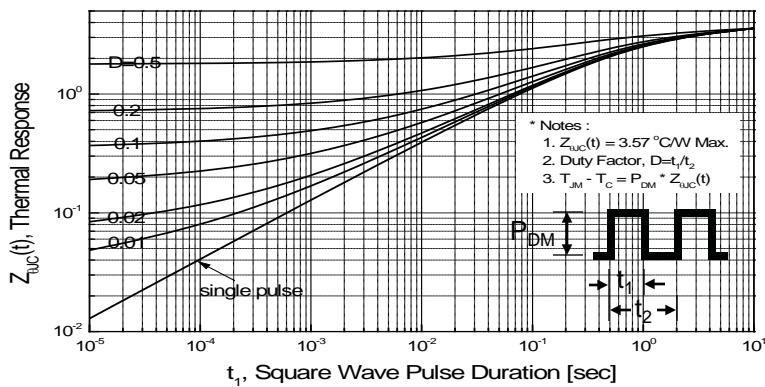
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Maximum Drain Current vs Case Temperature**



**Figure 11. Transient Thermal Response Curve**

Fig 12. Gate Charge Test Circuit &amp; Waveform

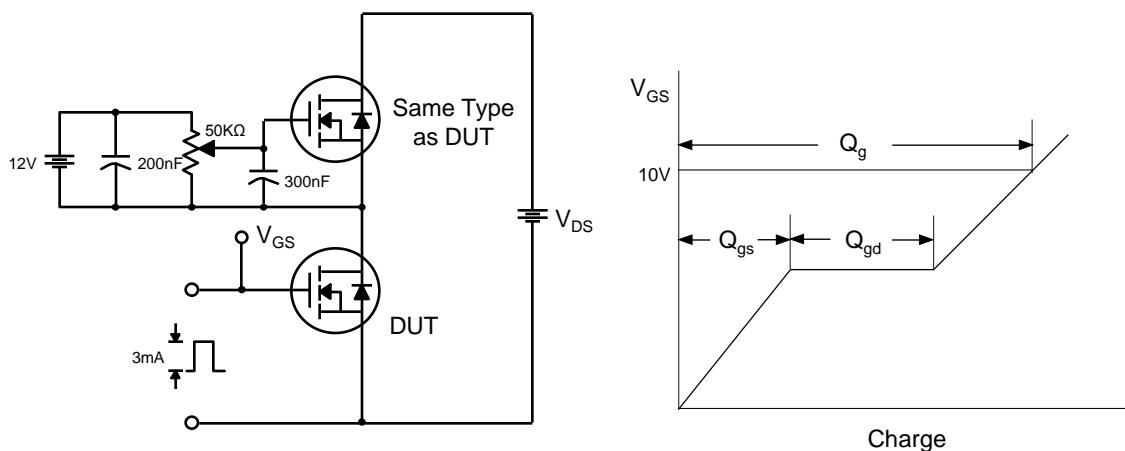


Fig 13. Resistive Switching Test Circuit &amp; Waveforms

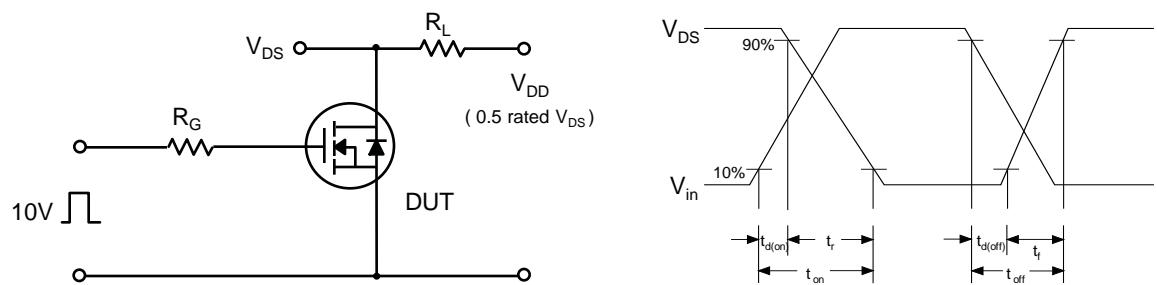


Fig 14. Unclamped Inductive Switching Test Circuit &amp; Waveforms

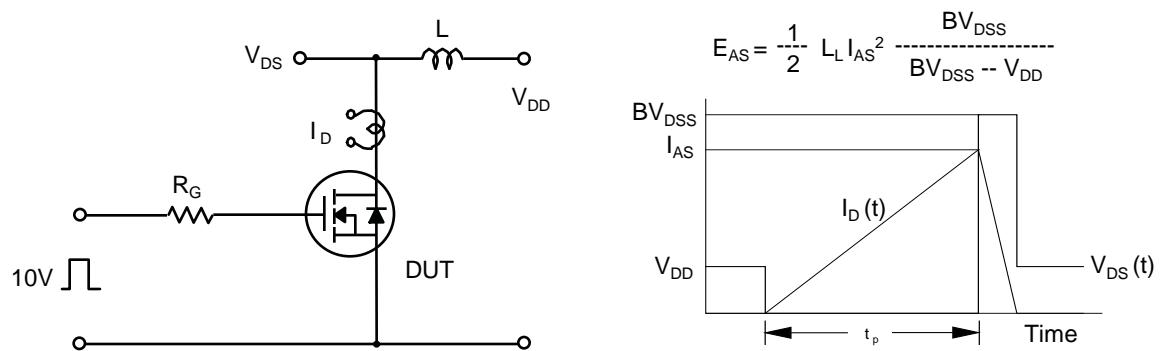
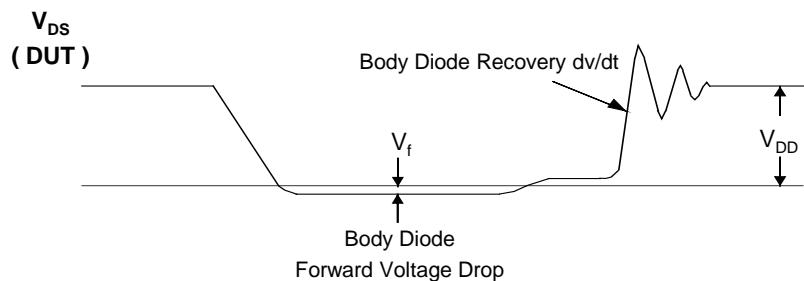
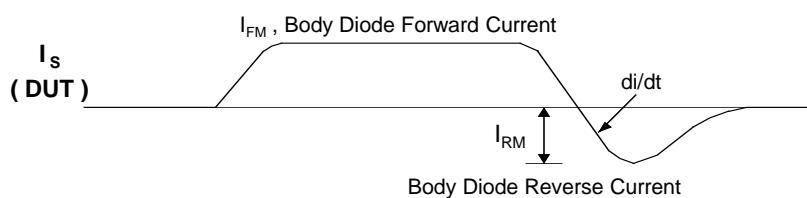
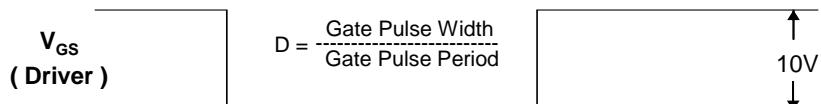
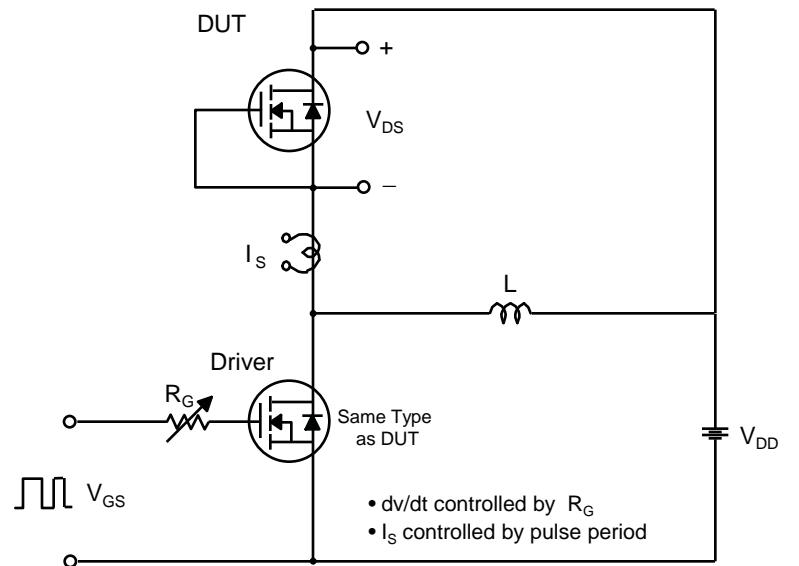


Fig 15. Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms



**HFSN40**

## Package Dimension

**TO-220F**

